

Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features

- ◆ 80V,60A, $R_{DS(on),max}=16m\Omega @ V_{GS}=10V$
- ◆ Improved dv/dt capability
- ◆ Fast switching
- ◆ 100% EAS Guaranteed
- ◆ Green device available

Applications

- ◆ Motor Drives
- ◆ UPS
- ◆ DC-DC Converter

Product Summary

V_{DSS}	80V
$R_{DS(on),max} @ V_{GS}=10V$	16mΩ
I_D	60A

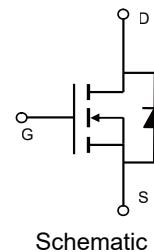
Pin Configuration



TO-263



TO-220C



Absolute Maximum Ratings

$T_C = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	80	V
Continuous drain current ($T_C = 25^\circ C$)	I_D	60	A
Continuous drain current ($T_C = 100^\circ C$)		39	A
Pulsed drain current ¹⁾	I_{DM}	240	A
Gate-Source voltage	V_{GSS}	± 20	V
Avalanche energy ²⁾	E_{AS}	132	mJ
Power Dissipation ($T_C = 25^\circ C$)	P_D	110	W
Storage Temperature Range	T_{STG}	-55 to +150	°C
Operating Junction Temperature Range	T_J	-55 to +150	°C

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.13	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62	°C/W

Package Marking and Ordering Information

Device	Device Package	Marking
VSM60N08-T3	TO-263	VSM60N08-T3
VSM60N08-TC	TO-220C	VSM60N08-TC

Electrical Characteristics

T_J = 25°C unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV _{DSS}	V _{GS} =0 V, I _D =250μA	80	---	---	V
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	1.0	1.6	2.5	V
Drain-source leakage current	I _{DSS}	V _{DS} =80V, V _{GS} =0V, T _J = 25°C	---	---	1	μA
		V _{DS} =64V, V _{GS} =0V, T _J = 125°C	---	---	30	μA
Gate leakage current, Forward	I _{GSSF}	V _{GS} =20 V, V _{DS} =0 V	---	---	100	nA
Gate leakage current, Reverse	I _{GSSR}	V _{GS} =-20 V, V _{DS} =0 V	---	---	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D = 30 A	---	12.5	16	mΩ
		V _{GS} =4.5 V, I _D =20 A	---	16.5	21	mΩ
Forward transconductance	g _f	V _{DS} =10V , I _D =30A	---	52	---	S
Dynamic characteristics						
Input capacitance	C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, F = 1MHz	---	3116	---	pF
Output capacitance	C _{oss}		---	196	---	
Reverse transfer capacitance	C _{rss}		---	140	---	
Turn-on delay time	t _{d(on)}	V _{DD} =40V, V _{GS} =10V, I _D = 30A	---	10.7	---	ns
Rise time	t _r		---	17.7	---	
Turn-off delay time	t _{d(off)}		---	139.7	---	
Fall time	t _f		---	28.3	---	
Gate resistance	R _g	V _{GS} =0V, V _{DS} =0V, F=1MHz	---	1.5	---	Ω
Gate charge characteristics						
Gate to source charge	Q _{gs}	V _{DS} =40 V, I _D =30A, V _{GS} = 10 V	---	13.6	---	nC
Gate to drain charge	Q _{gd}		---	11.7	---	
Gate charge tota	Q _g		---	58	---	
Drain-Source diode characteristics and Maximum Ratings						
Diode Forward Voltage ³⁾	V _{SD}	V _{GS} =0V, I _S =30A, T _J =25°C	---	0.85	1.3	V
Reverse Recovery Time	t _{rr}	I _S =30A, di/dt=100A/us, T _J =25°C	---	27.7	---	ns
Reverse Recovery Charge	Q _{rr}		---	41	---	nC

Notes:

1: Repetitive Rating: Pulse width limited by maximum junction temperature.

2: V_{DD}=50V, V_{GS}=10V, L=0.5mH, I_{AS}=23A, R_G=25Ω, Starting T_J=25°C.

3: Pulse Test: Pulse Width ≤300 μ s, Duty Cycle≤2%.

Electrical Characteristics Diagrams

Figure 1. Typ. Output Characteristics

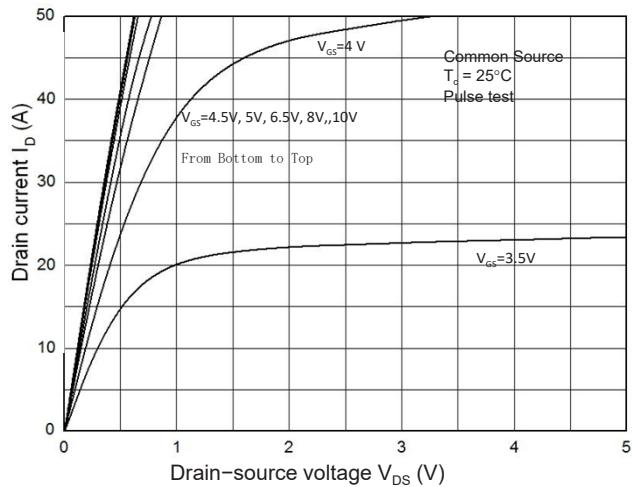


Figure 2. Transfer Characteristics

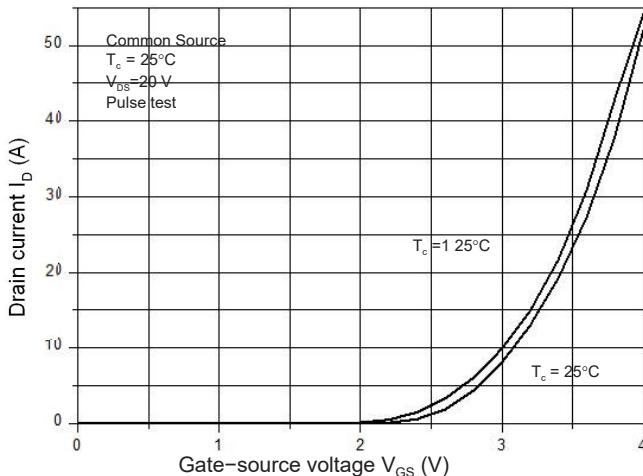


Figure 3. Capacitance Characteristics

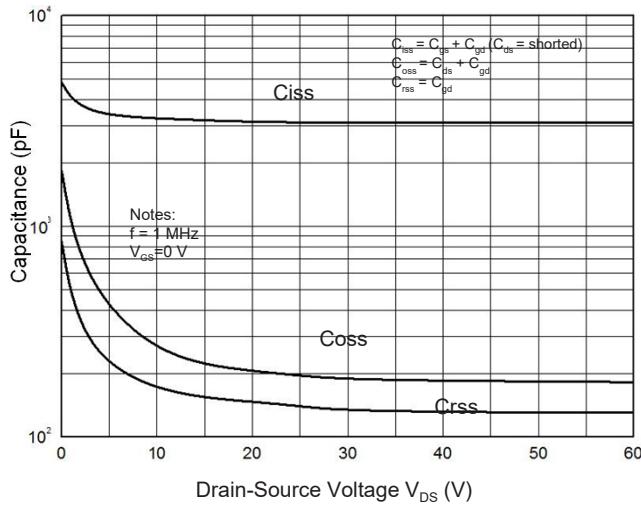


Figure 4. Gate Charge Waveform

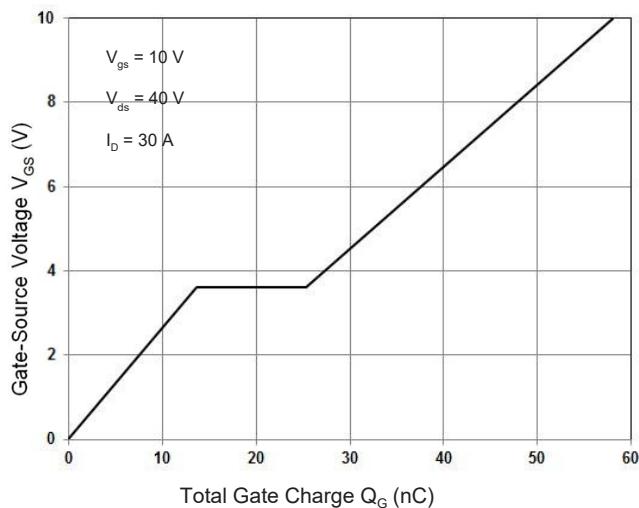


Figure 5. Body-Diode Characteristics

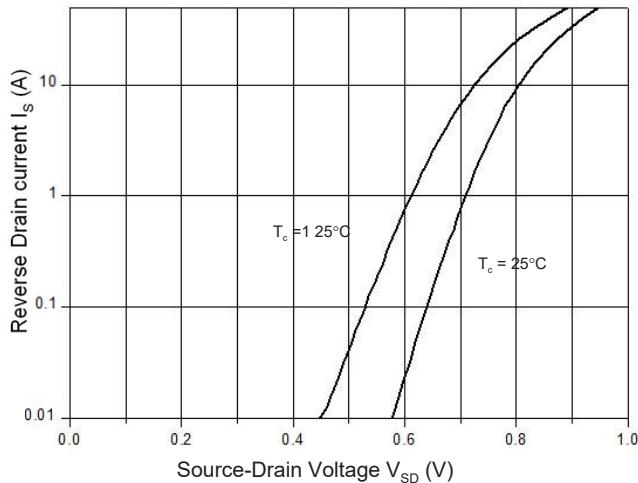


Figure 6. Rdson-Drain Current

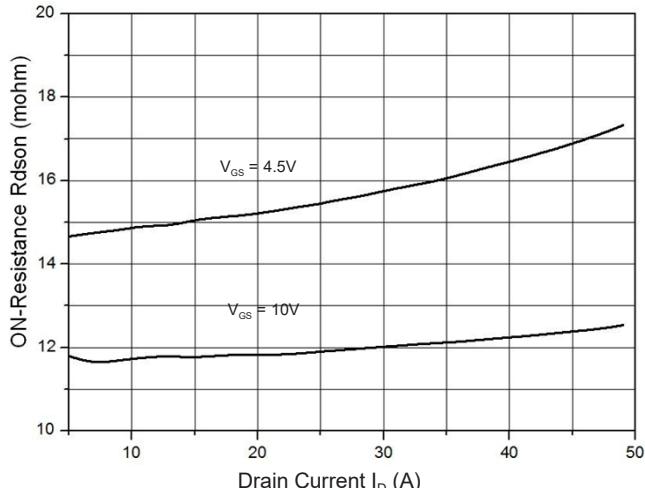


Figure 7. Rdson-Junction Temperature(°C)

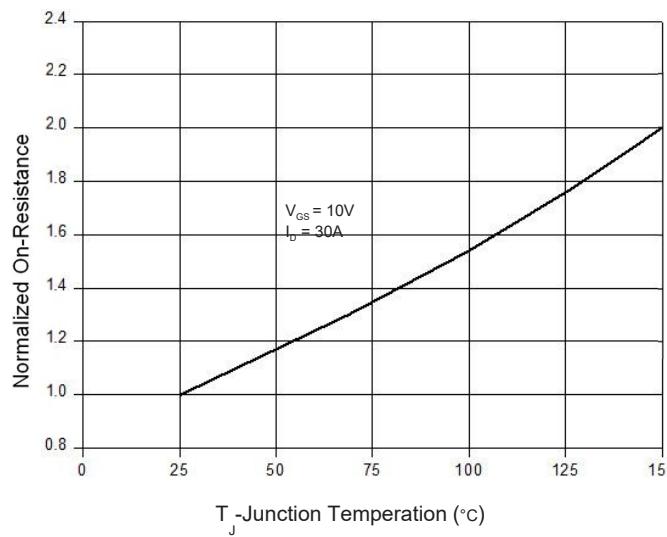


Figure 8. Maximum Safe Operating Area

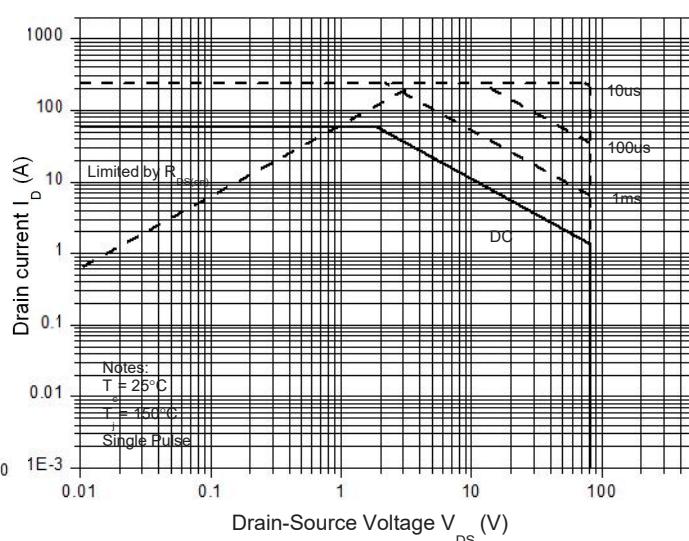
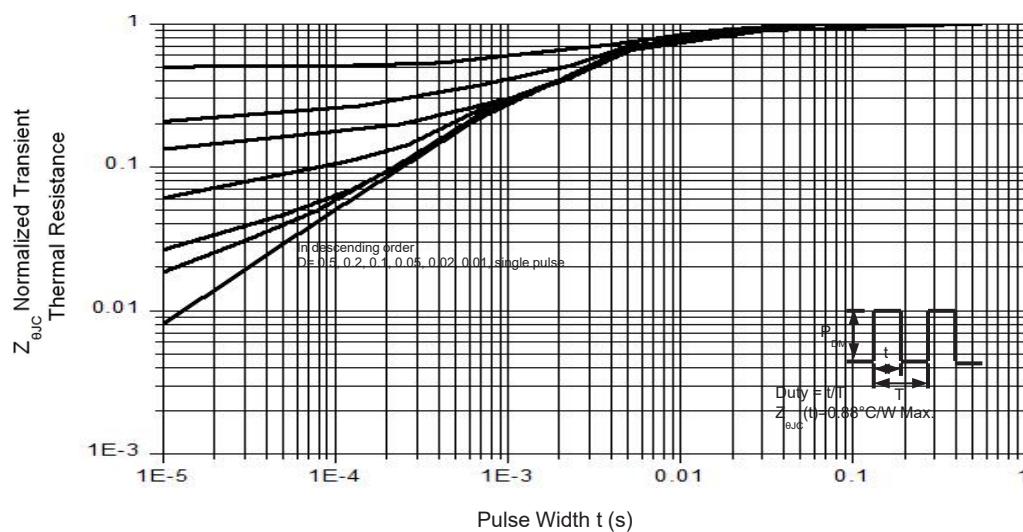


Figure 9. Normalized Maximum Transient Thermal Impedance (RthJC)



Test Circuit & Waveform

Figure 8. Gate Charge Test Circuit & Waveform

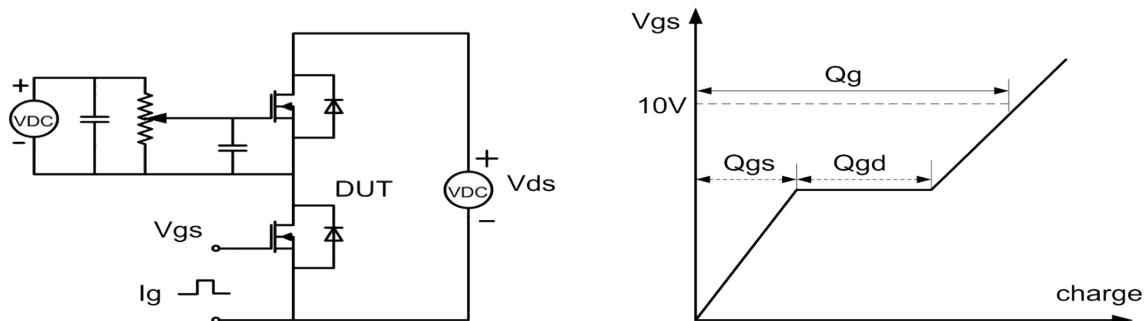


Figure 9. Resistive Switching Test Circuit & Waveforms

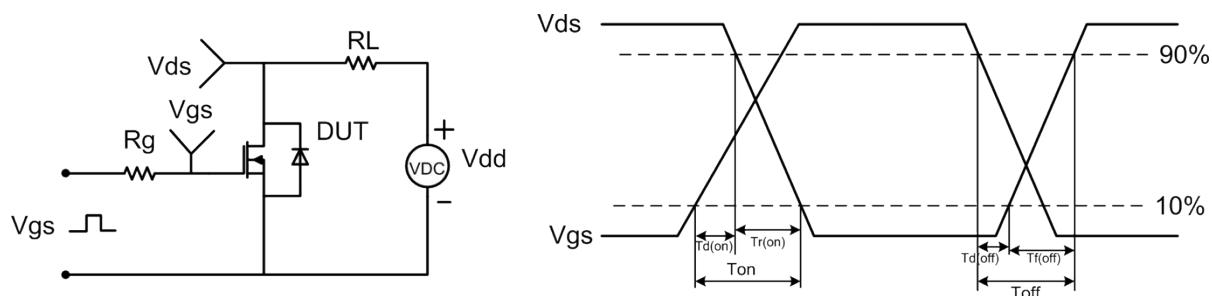


Figure 10. Unclamped Inductive Switching (UIS) Test Circuit & Waveform

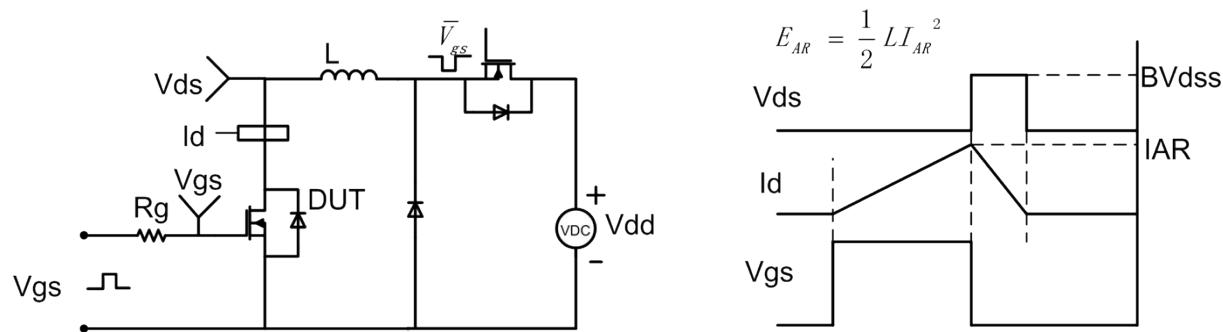


Figure 11. Diode Recovery Circuit & Waveform

